## nexperia

## **Quarterly Reliability Monitoring Results**

Quarters: Q1/2022 to Q4/2023 Based on structural similarity

Supplier		User Part Number						
Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		BAV70W-Q Part Description						
								Nexperia DHAM Small Signal Bipolar Diode
		SMD package						
		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
			TEST					
	Pre- and Post-Stress							
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		JESD22-A113	.,					
		Bake Tamb = 125 °C	24 hours					
	PC	Soak Tamb = $85 ^{\circ}$ C, RH = $85\%$	168 hours					
# A1	Preconditioning	Reflow soldering	3 cycles	1514	64430	0		
		MIL-STD-750-1						
	HTRB	M1038 Method A						
		$T_j = T_j max$ , $Vr = 100\%$ of max. datasheet						
# B1	Bias	reverse voltage	1000 hours	110	4920	0		
			2000 110015			•		
	тс	JESD22-A104						
# A4	Temperature Cycling	-65 °C to Timax, not to exceed 150°C	1000 cycles	311	14080	0		
	· · · · · · · · · · · · · · · · · · ·		1000 cycles	511	11000	0		
	UHAST	JESD22-A118						
# A3 or	Unbiased HAST	Tamb = 130 °C, RH = 85 %						
		,	— 96 hours	311	14080	0		
# A3 alt	AC	JESD22-A102 Tamb = 121 °C, RH = 100 %						
	Autoclave	Pressure = $205 \text{ kPa} (29.7 \text{ psia})$						
# A5 dit	Autociave	Pressure – 203 kPa (23.7 psia)						
	H3TRB	JESD22-A101						
		Tamb = $85 ^{\circ}$ C, RH = $85\%$ , VR = $80\%$ of						
# 40 alt	High Humidity High Temperature Reverse Bias		1000 hours	211	14000	0		
# A2 alt	remperature Reverse Blas		1000 hours	311	14080	0		
		MIL-STD-750 Method 1037						
	IOL	ton = toff, devices powered to insure $\Delta T j =$	1000	242				
# A5	Intermittent Operating Life	100 °C for 15000 cycles	1000 hours	312	14120	0		
	RSH	JESD22-A111						
# C8	Resistance to Solder Heat	260 °C ± 5 °C	10 s	269	8070	0		
	SD							
# C10	Solderability	J-STD-002		222	6660	0		

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Small Signal Bipolar Diode	4920	0	0,86	1,16E+09

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